MOSFET – Power, N-Channel, SUPERFET[®] III 800 V, 600 mΩ, 8 A

NTD600N80S3Z

Description

800 V SUPERFET III MOSFET is ON Semiconductor's high performance MOSFET family offering 800 V breakdown voltage.

New 800 V SUPERFET III MOSFET which is optimized for primary switch of flyback converter, enables lower switching losses and case temperature without sacrificing EMI performance thanks to its optimized design. In addition, internal Zener Diode significantly improves ESD capability.

This new family of 800 V SUPERFET III MOSFET enables to make more efficient, compact, cooler and more robust applications because of its remarkable performance in switching power applications such as Laptop adapter, Audio, Lighting, ATX power and industrial power supplies.

Features

- Typ. $R_{DS(on)} = 550 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q_g = 15.5 nC)
- Low Stored Energy in Output Capacitance (Eoss = 1.74 μJ @ 400 V)
- 100% Avalanche Tested
- ESD Improved Capability with Zener Diode
- RoHS Compliant

Applications

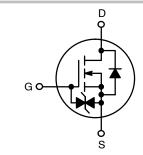
- Adapters / Chargers
- LED Lighting
- AUX Power
- Audio
- Industrial Power



ON Semiconductor®

www.onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
800 V	600 m $Ω$	8 A



POWER MOSFET



MARKING DIAGRAM



T600N80S3Z

= Specific Device Code

A

Assembly LocationYear

Y WW

= Work Week

ZZ

= Lot Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

ABSOLUTE MAXIMUM RATINGS ($T_J = 25^{\circ}C$, unless otherwise noted)

Symbol	Param	Value	Unit	
V_{DSS}	Drain-to-Source Voltage		800	V
V_{GS}	Gate-to-Source Voltage	DC	±20	V
		AC (f > 1 Hz)	±30	1
I _D	Drain Current	Continuous (T _C = 25°C)	8*	Α
		Continuous (T _C = 100°C)	5*	1
I _{DM}	Drain Current	Pulsed (Note 1)	21*	Α
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		24	mJ
I _{AS}	Avalanche Current (Note 2)		1.2	Α
E _{AR}	Repetitive Avalanche Energy (Note 1)		0.6	mJ
dv/dt	MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note 3)	10	1	
P_{D}	Power Dissipation	(T _C = 25°C)	60	W
		Derate Above 25°C	0.48	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T_L	Lead Temperature Soldering Reflow for Soldering Purposes (1/8" from Case for 10 seconds)		260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. *Drain current limited by maximum junction temperature.

1. Repetitive rating: pulse–width limited by maximum junction temperature.

2. $I_{AS} = 1.2 \text{ A}$, $R_G = 25 \Omega$, starting $T_J = 25^{\circ}\text{C}$.

3. $I_{SD} \le 2 \text{ A}$, di/dt $\le 200 \text{ A}/\mu\text{s}$, $V_{DD} \le 400 \text{ V}$, starting $T_J = 25^{\circ}\text{C}$.

THERMAL RESISTANCE RATINGS

Symbol	Parameter	Value	Unit
$R_{ heta JC}$	Junction-to-Case - Steady State	2.08	°C/W
$R_{ heta JA}$	Junction-to-Ambient - Steady State	62.5	

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Reel Size	Tape Width	Quantity
NTD600N80S3Z	NTD600N80S3Z	TO-252	330 mm	16 mm	2500 Units

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHARACT	ERISTICS				_	
BV_DSS	Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	800			V
		V _{GS} = 0 V, I _D = 1 mA, T _J = 150°C	900			V
$\Delta BV_{DSS}/\Delta T_{J}$	Drain-to-Source Breakdown Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C		1.1		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 800 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 640 V, T _C = 125°C		0.8		
I _{GSS}	Gate-to-Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			1	μΑ
ON CHARACTE	ERISTICS				-	
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 0.18 \text{ mA}$	2.2		3.8	V
R _{DS(on)}	Static Drain-to-Source On Resistance	V _{GS} = 10 V, I _D = 4 A		550	600	mΩ
9FS	Forward Transconductance	V _{DS} = 20 V, I _D = 4 A		9.4		S
DYNAMIC CHA	RACTERISTICS			•		•
C _{iss}	Input Capacitance	V _{DS} = 400 V, V _{GS} = 0 V, f = 250 kHz		725		pF
C _{oss}	Output Capacitance			12		pF
C _{oss(eff.)}	Effective Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V		139		pF
C _{oss(er.)}	Energy Related Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V		21		pF
Q _{g(tot)}	Total Gate Charge at 10 V	$V_{DD} = 400 \text{ V}, I_D = 4 \text{ A}, V_{GS} = 10 \text{ V}$		15.5		nC
Q _{gs}	Gate-to-Source Gate Charge	(Note 4)		3.1		nC
Q _{gd}	Gate-to-Drain "Miller" Charge			5.1		nC
ESR	Equivalent Series Resistance	f = 1 MHz		3.5		Ω
SWITCHING CH	HARACTERISTICS				-	
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, I_D = 4 \text{ A}, V_{GS} = 10 \text{ V},$		12.3		ns
t _r	Turn-On Rise Time	$R_g = 4.7 \Omega$ (Note 4)		5.9		ns
t _{d(off)}	Turn-Off Delay Time			39.5		ns
t _f	Turn-Off Fall Time			8.2		ns
SOURCE-TO-I	DRAIN DIODE CHARACTERISTICS				_	•
I _S	Maximum Continuous Source-to-Drain Diode Forward Current				8	Α
I _{SM}	Maximum Pulsed Source-to-Drain Diode Forward Current				21	Α
V _{SD}	Source-to-Drain Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 4 A			1.2	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 2 A,		137		ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt = 100 A/μs		0.91		μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

SUPERFET is a registered trademark of Semiconductor Components Industries, LLC (SCILLC) or its subsidiaries in the United States and/or other countries.

^{4.} Essentially independent of operating temperature typical characteristics.

TYPICAL CHARACTERISTICS

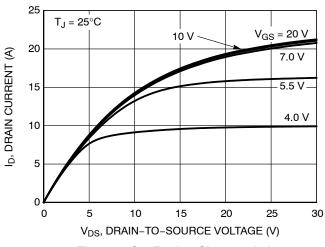


Figure 1. On-Region Characteristics

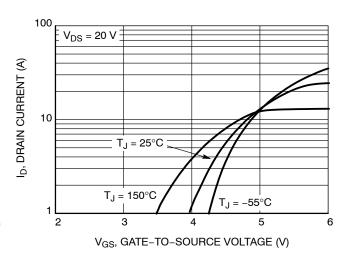


Figure 2. Transfer Characteristics

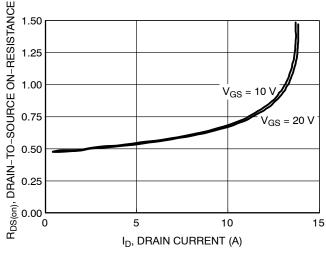


Figure 3. On Resistance vs. Drain Current

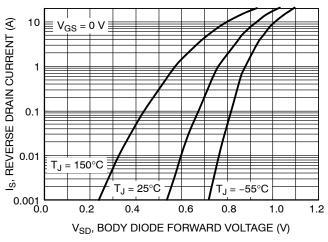


Figure 4. Diode Forward Voltage vs. Current

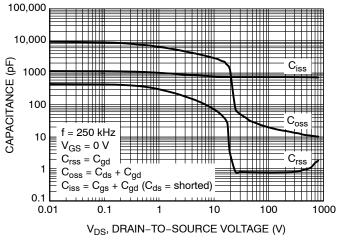


Figure 5. Capacitance Characteristics

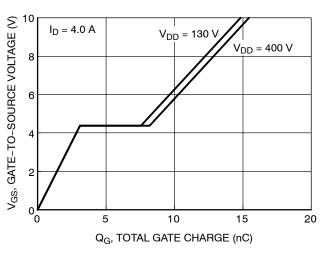


Figure 6. Gate Charge Characteristics

TYPICAL CHARACTERISTICS

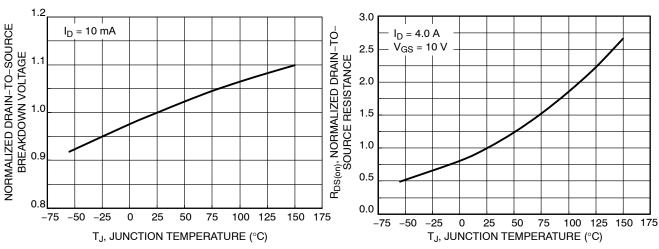


Figure 7. Normalized BV_{DSS} vs. Temperature

Figure 8. On–Resistance Variation vs.
Temperature

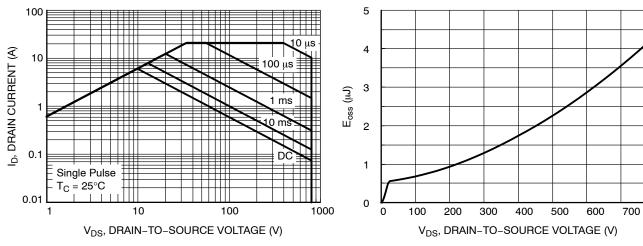


Figure 9. Safe Operating Area

Figure 10. E_{oss} vs. Drain-to-Source Voltage

8

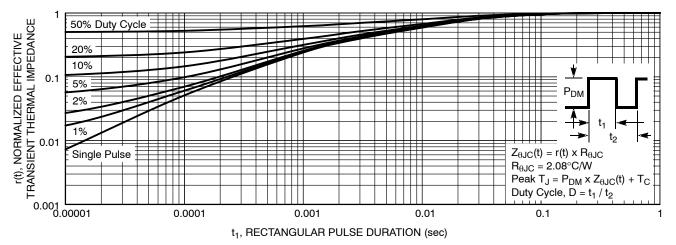


Figure 11. Transient Thermal Impedance

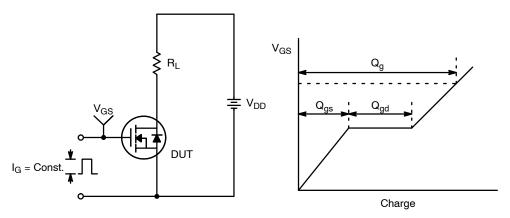


Figure 12. Gate Charge Test Circuit & Waveform

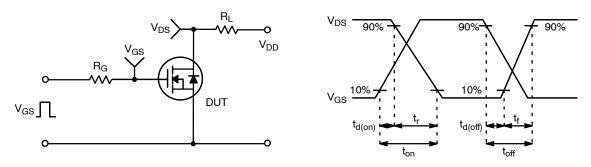


Figure 13. Resistive Switching Test Circuit & Waveforms

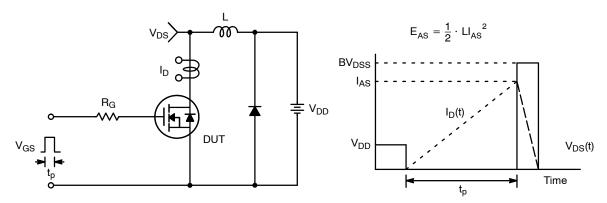


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

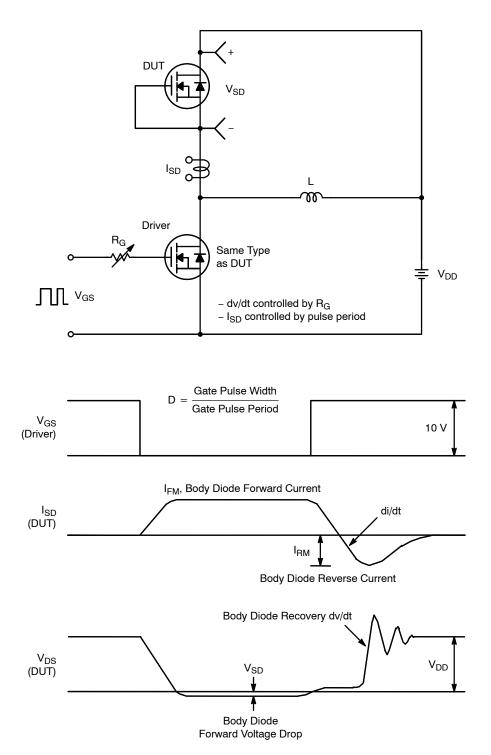
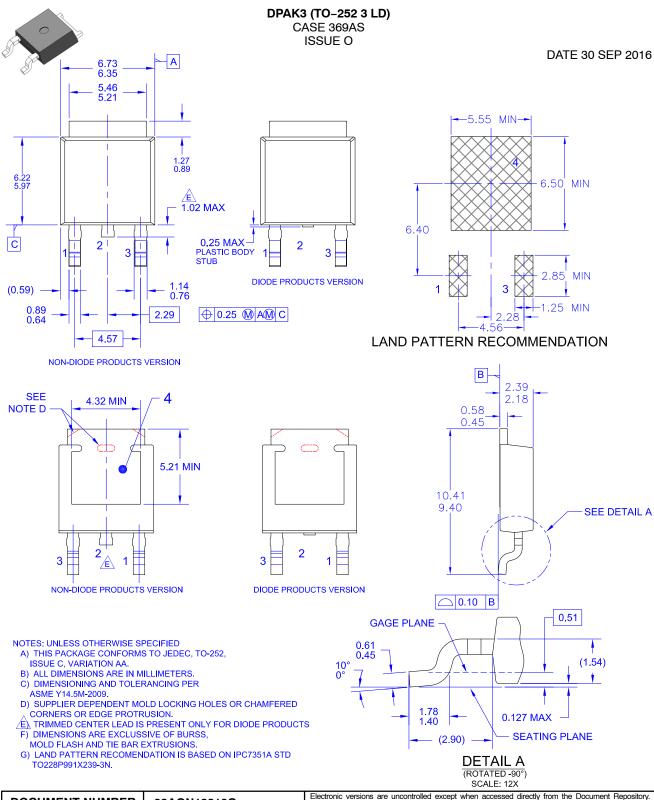


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms





DOCUMENT NUMBER:	98AON13810G	Electronic versions are uncontrolled except when accessed directly from the Document Repository Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	DPAK3 (TO-252 3 LD)		PAGE 1 OF 1	

onsemi and ONSemi are trademarks of Semiconductor Components Industries, LLC dba onsemi or its subsidiaries in the United States and/or other countries. onsemi reserves the right to make changes without further notice to any products herein. onsemi makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. onsemi does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMi., and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. Onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer p

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT: Email Requests to: orderlit@onsemi.com

onsemi Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative